IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:	H. MIURA et al.
Serial No.:	Rule 1.53(b) Continuation of U.S. Patent Application Serial No. 09/893,980 filed June 29, 2001
Filed:	July 25, 2003
For:	SEMICONDUCTOR MEMORY DEVICE
Art Group of Parent:	2818
Examiner of Parent:	Long K. Tran

INFORMATION DISCLOSURE STATEMENT
UNDER 37 C.F.R. §1.97 AND §1.98

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

July 25, 2003

Sir:

This Information Disclosure Statement is being filed in accordance with 37 C.F.R. §1.97 along with a Form PTO-1449. This Information Disclosure Statement is being filed simultaneously with the filing of this application.

This application claims priority under 35 U.S.C. §120 from parent Application Nos. 09/893,980, filed June 29, 2001, 08/838,259, filed April 17, 1997, and 08/270,472, filed July 5, 1994. Thus, in accordance with 37 C.F.R. §1.98(d), copies of the references cited or submitted in the parent applications do not need to be filed by the applicant.

It is respectfully requested that this Information Disclosure Statement be considered by the Examiner.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to the deposit account of Antonelli, Terry, Stout & Kraus, Deposit Account No. 01-2135 (500.33045CC3) and please credit any excess fees to such Deposit Account.

Respectfully submitted,

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PTO/SB/08A (10-01)
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Substitute for form 1449A/PTO				**Complete if Known**	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Application Number	
				Filing Date	July 25, 2003
				First Named Inventor	MIURA et al.
				Art Unit	Unassigned
(use as many sheets as necessary)				Examiner Name	Unassigned
Sheet	1	of	1	Attorney Docket Number	500.33045CC3

U.S. PATENT DOCUMENTS

Examiner Initials'	Cite No.[1]	Document Number Number-Kind Code[2] *(if known)*		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US-4,839,306		06/1989	Wakamatsu	
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Examiner Initials'	Cite No.[1]	Foreign Patent Document Country Code[3]–Number[4]–Kind Code[5] *(if known)*	Publication Date MM-DD-YYYY	Country	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T[6]
		JP 3-96249	04/1991	Japan (Abstract only)		
		JP 3-236283	10/1991	Japan		
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Chiu et al., "A Bird's Beak Free Local Oxidation Technology Feasible for VLSI Circuits Fabrication", IEEE TRANSACTIONS ON ELECTRON DEVICES, Vo. ED-29, No. 4, 1983, pages 536-540

Examiner Signature		Date Considered	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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